Statistical analysis : using SDD and Pad Chamber

- match tracks from SDD to Pad Chamber (**M**) by common Θ
- measure random tracks from event mixing (**B**)
- extract signal $\mathbf{S} = (\mathbf{M} - \mathbf{B})$ $\quad S/B \sim 2:1$
- measure momenta and charge by azimuthal Φ deflection

$$p = \frac{0.1\ rad}{\Delta\Phi} \text{ in GeV/c} \quad \text{and} \quad \frac{\delta p}{p}(p \to \infty) \sim 4\% \cdot p$$